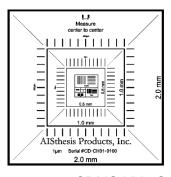
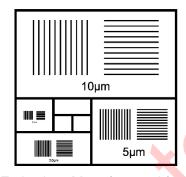


Advanced Imaging Products for Nanotechnology, Engineering and Life Sciences

Certificate of Calibration for Pelcotec™ XY-Critical Dimension Standard





Product Number: Pelcotec™ 705-1 CDMS-XY-1C-Etched

Product Description: 2.5x2.5mm Pelcotec™ 2mm-1µm XY-Critical Dimension Magnification Standard

Product Serial Number: CD-CH01-1234

Manufactured for and Distributed by:



The accuracy of these products was determined by reference comparison to working standards traceable to the National Institute of Standards and Technology (NIST).

| Line | Direction | Certified average pitch | Number of lines averaged | Certified distance between first and last line (1σ) | Total expanded uncertainty (3σ) |
|--------|-----------|-------------------------|--------------------------|---|---------------------------------|
| 2.0mm | Х | 2.00 mm | 2 | 2.00 mm ± 0.03% | ± 0.09% |
| 1.0mm | Х | 1.00 mm | 2 | 1.00 mm ± 0.03% | ± 0.09% |
| 0.5mm | Х | 0.500 mm | 2 | 0.500 mm ± 0.03% | ± 0.09% |
| 0.10mm | Х | 100.04 µm | 11 | 1.00 mm ± 0.03% | ± 0.09% |
| 50µm | Х | 50.00 μm | 11 | 0.500 mm ± 0.03% | ± 0.09% |
| 10µm | Х | 10.00 µm | 11 | 100.04 μm ± 0.03% | ± 0.09% |
| 5µm | Х | 5.01 µm | 12 | 55.10 µm ± 0.03% | ± 0.09% |
| 2µm | Х | 2.01 µm | 16 | 30.13 μm ± 0.03% | ± 0.09% |
| 1µm | Х | 1.00 µm | 17 | 16.07 µm ± 0.03% | ± 0.09% |
| | | | | | |
| 2.0mm | Υ | 2.00 mm | 2 | 2.00 mm ± 0.03% | ± 0.09% |
| 1.0mm | Y | 1.00 mm | 2 | 1.00 mm ± 0.03% | ± 0.09% |
| 0.5mm | Y | 0.500 mm | 2 | 0.500 mm ± 0.03% | ± 0.09% |
| 0.10mm | Y | 100.13 µm | 11 | 1.00 mm ± 0.03% | ± 0.09% |
| 50µm | Υ | 50.00 µm | 11 | 0.500 mm ± 0.03% | ± 0.09% |
| 10µm | Y | 10.01 µm | 11 | 100.13 μm ± 0.03% | ± 0.09% |
| 5µm | Υ | 5.01 µm | 12 | 55.12 µm ± 0.03% | ± 0.09% |
| 2µm | Υ | 2.01 µm | 16 | 30.15 μm ± 0.03% | ± 0.09% |
| 1µm | Υ | 1.01 µm | 17 | 16.08 µm ± 0.03% | ± 0.09% |

The certified average pitch is derived from the stated certified length that was determined using 10 measurements (taken center-to-center) over the stated number of lines (i.e., length divided by the number of lines minus one). The total expanded uncertainty includes both Type A and Type B uncertainties corrected for sample size using an appropriate Student t-factor.

Equipment used:

| Instrument | Model number | Serial # | NIST Certified CD | Resolution | Repeatability |
|------------|--------------|----------|-------------------|------------|---------------|
| FE-SEM | FEI Apreo 2 | 9958357 | CD-PG01-0211 | 0.9nm | 0.03% |

| _D.S. Finch | | 01/26/2024 |
|--------------|-----------|------------|
| Certified by | Signature | Date |

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